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INTERNATIONAL STANDARD

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Semiconductor devices – Micro-electromechanical devices – Part 40: Test methods of micro-electromechanical inertial shock switch threshold

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Part 40: Test methods of micro-electromechanical inertial shock switch threshold

FOREWORD

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IEC 62047-40 has been prepared by subcommittee 47F: Micro-electromechanical systems, of IEC technical committee 47: Semiconductor devices. It is an International Standard.

The text of this International Standard is based on the following documents:

DRAFT	Report on voting
47F/384/FDIS	47F/388/RVD

Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this International Standard is English.

This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in accordance with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement, available at www.iec.ch/members_experts/refdocs. The main document types developed by IEC are described in greater detail at www.iec.ch/standardsdev/publications.

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The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under webstore.iec.ch in the data related to the specific document. At this date, the document will be

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SEMICONDUCTOR DEVICES – MICRO-ELECTROMECHANICAL DEVICES –

Part 40: Test methods of micro-electromechanical inertial shock switch threshold

1 Scope

This part of IEC 62047 specifies the test conditions and methods of micro-electromechanical inertial shock switch threshold. This document applies to normally open micro-electromechanical inertial shock switch.

2 Normative references

There are no normative references in this document.

3 Terms and definitions

For the purposes of this document, the following terms and definitions apply.

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

- IEC Electropedia: available at http://www.electropedia.org/
- ISO Online browsing platform: available at http://www.iso.org/obp

3.1
micro-electromechanical shock inertial switch
device that is fabricated by micro-electromechanical system technology, and is closed or open via the contact or separation of fixed and movable electrode under or above a certain acceleration, also as known threshold switch, acceleration switch, or g switch